EEIE30069: VLSI Testing

Assignment 6

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I. Compile and execute

```
-- How to compile:
In /podem directory, enter the following command:
     $ make
     It will generate the executable file "atpg" in this directory
-- How to run:
In /podem directory, enter the following command:
For 1.-a:
     $ ./run.sh ass6 a [backtrack num]
     (will use b17.bench to run atpg)
     e.g.:
          $ ./run.sh ass6 a 100
For 1.-b:
     $ ./run.sh ass6_b1 (atpg with checkpoint fault list and run fsim)
     $ ./run.sh ass6 b2 (atpg with total fault list and run fsim)
     e.g.:
          $./run.sh ass6 b
For 1.-c
     $ ./run.sh ass6_c (print c17 procedure)
     e.g.:
          $./run.sh ass6 c
For 1.-d
     $ ./run.sh ass6 d [circuit name]
```

e.g.:

\$./run.sh ass6 d

For 1.-e

\$./run.sh ass6 e [circuit name]

e.g.:

\$./run.sh ass6 e b17

II. Overview of my method

For 1.-d

In the first stage, we will generate 1000 patterns, and this pattern will used to do fault simulations one by one. If the coverage reaches 90%, then break the while loop and run the original atpg in the second stage. If not, it will test all 1000 pattern, and run the original atpg in the second stage as well.

For 1.-e

The program is written in bfatpg.cc. The program will use bridging fault list to run PODEM. The program will compare two net values the pattern gives and decide whether the pattern can detect the bridging fault. The table below shows the detected bridging fault pattern.

| original | Wired-OR | Wired-AND |
|----------|------------|-----------|
| ab | a⁺ b⁺ | a⁺ b⁺ |
| 0 0 | 0 0 | 0 0 |
| 0 1 | <u>1</u> 1 | 0 0 |
| 10 | 1 <u>1</u> | 0 0 |
| 11 | 1 1 | 1 1 |

III. Result and analysis

For 1. -a (b17) backtrack limits=1

number of patterns: 41647

fault coverages: 55%

CPU run times: 785.01

actual backtrack numbers: 68413

For 1. -a (b17) backtrack limits=10

number of patterns: 72511

fault coverages: 82.09%

CPU run times: 1285.96

actual backtrack numbers: 376982

For 1. -a (b17) backtrack limits=100

number of patterns: 84711

fault coverages: 90.01%

CPU run times: 1496.43

actual backtrack numbers: 1821691

```
backtrack limit = 100
Test pattern number = 83711
Total backtrack number = 1821691
Total fault number = 142884
Detected fault number = 128608
Undetected fault number = 14276
Abort fault number = 13584
Redundant fault number = 692
Total equivalent fault number = 142884
Equivalent detected fault number = 128608
Equivalent undetected fault number = 14276
Equivalent abort fault number = 13584
Equivalent redundant fault number = 692
Fault Coverge = 90.01%
Equivalent FC = 90.01%
ault Efficiency = 90.45%
total CPU time = 1496.43
```

For 1. -a (b17) backtrack limits=1000

number of patterns: 86025

fault coverages: 91.62%

CPU run times: 3942.69

actual backtrack numbers: 12664818

For 1.-b

test vector with checkpoint fault list(left), fsim on the total fault list(right)

```
Generate checkpoint fault list
Run stuck-at fault ATPG
compute fault coverage
backtrack limit = 1
Test pattern number = 25694
Total backtrack number = 40088
Total fault number = 81330
Detected fault number = 43157
Undetected fault number = 38173
Abort fault number = 37802
Redundant fault number = 371
Total equivalent fault number = 81330
Equivalent detected fault number = 43157
Equivalent undetected fault number = 38173
Equivalent abort fault number = 37802
Equivalent redundant fault number = 371
Fault Coverge = 53.06%
Equivalent FC = 53.06%
 ault Efficiency = 53.31%
total CPU time = 295.63
```

test vector with total fault list(left), fsim on the total fault list (right)

```
Run stuck-at fault simulation

Test pattern number = 41647

Parallel PatternNum: 16

Total fault number = 142884

Detected fault number = 20530

Equivalent fault number = 142884

Equivalent detected fault number = 122354

Equivalent detected fault number = 20530

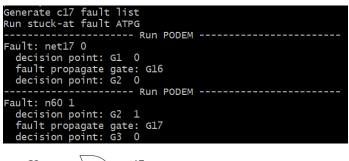
Fault Coverge = 85.63%

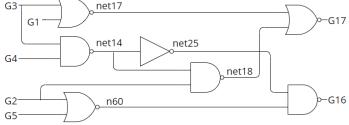
Equivalent FC = 85.63%

Equivalent CPU time = 182.44
```

From the result, we can see that the test vector with a checkpoint fault list generates fewer pattern number than the test vector with a total fault. The fault coverage is different, the test vector with the total fault list has a higher coverage. However, it needs much more CPU runtime and pattern number.

For 1.-c





In net17 s.a.0 case, fault activation set net17=1, we can find the decision G1=0, then fault propagate to G16, and new decision point is G2=0

In n60 s.a.1 case, fault activation set n60=0, we can find the decision G2=1, then fault propagate to G17, and new decision point is G3=0

Both net17 s.a.0 and n60 s.a.1 no need to backtrack the decision to find the test pattern.

For 1.-d

For b17,bench

For s35932 com

For s38417 com

For s38584 com

Using a random pattern in the first stage, we can find out that it can significantly reduce the CPU run time to run ATPG in the second stage.

For 1.-e bridging fault atpg(left), bridging fault simulation(right)

```
run bridging fault ATPG
Generate bridging fault list
Bridging fault number:16
Run bridging fault ATPG

Test pattern number = 7
Total backtrack number = 13
Backtrack limit = 10000

Total fault number = 16
Detected fault number = 3
Abort fault number = 0
Redundant fault number = 3

Total equivalent fault number = 13
Equivalent detected fault number = 3
Equivalent undetected fault number = 3
Equivalent abort fault number = 0
Equivalent redundant fault number = 3

Fault Coverge = 81.25%
Equivalent FC = 81.25%
Fault Efficiency = 100.00%

total CPU time = 0.00
```